

Notice of References Cited	Application/Control No. 10/590,872		Applicant(s)/Patent Under Reexamination TAKAI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0026085 A1	02-2003	Ueda et al.	362/31
*	B	US-2004/0070328 A1	04-2004	Van den Bergh et al.	313/461
*	C	US-2004/0125458 A1	07-2004	Chen et al.	359/599
*	D	US-2004/0251837 A1	12-2004	Leung et al.	315/076
*	E	US-2005/0246958 A1	11-2005	Weder, Donald E.	047/072
*	F	US-2005/0276072 A1	12-2005	Hayashi et al.	362/609
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	Q					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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